

Special Issue

Bayesian Statistics on Artificial Intelligence: Theory, Methods and Applications

Message from the Guest Editor

We are inviting submissions to the Special Issue on Bayesian Statistics on Artificial Intelligence: Theory, Methods and Applications. Bayesian statistics are based on Bayesian inference that consists of prior, likelihood, and posterior distributions. Using Bayesian inference, Bayesian learning represents the update of human beliefs about events as a probability distribution. Thus, Bayesian statistics is one of popular fields in artificial intelligence (AI). Bayesian neural networks and Bayesian deep learning are the results of Bayesian statistics applied to AI. We know that Bayesian statistics are making various contributions to more AI domains. So, in this Special Issue, we invite submissions on diverse methods and applications of Bayesian statistics on AI. We welcome not only theoretical studies on Bayesian statistics for artificial intelligence but also various applied studies.

Guest Editor

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Deadline for manuscript submissions

closed (20 July 2023)



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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